Problems of noise modeling in the presence of total current branching in HEMTs and FETs channels

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Outline

- Current branching
- Circuit model
- Analytical model
- Results
- Open problems

Conservation of total current

• Maxwell eqs. \rightarrow conservation of total current \rightarrow Kirchhoff law

$$\oint_{S} \mathbf{j}_{tot} d\mathbf{S} = 0$$

$$\mathbf{j}_{tot} = \varepsilon_{\varepsilon_{0}} \frac{\partial \mathbf{E}}{\partial t} + \mathbf{j}_{d}$$

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$$\mathbf{j}_{tot} = \mathbf{j}_{tot}$$

No branching \rightarrow 2 terminals \rightarrow Diode



 $\frac{\partial [S(x)j_{tot}(x,t)]}{\partial x} = 0$

No branching \rightarrow 2 terminals \rightarrow Diode





 $\frac{\partial [S(x)j_{tot}(x,t)]}{\partial x} = 0$



No branching \rightarrow 2 terminals \rightarrow Diode











1st consequence: Ramo-Shockley theorem

$$I_{tot} = \frac{e}{L} \sum_{i=1}^{N} v_i - \epsilon \epsilon_0 \frac{\partial}{\partial t} \Delta U$$

 ΔU



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$$I_{tot} = \frac{e}{L} \sum_{i=1}^{N} v_i - \frac{\epsilon \epsilon_0}{\partial t} \frac{\partial}{\partial t} \Delta U$$

displacement

 ΔU



1st consequence: Ramo-Shockley theorem

$$I_{tot} = \frac{e}{L} \sum_{i=1}^{N} v_i - \epsilon \epsilon_0 \frac{\partial}{\partial t} \Delta U$$

 $\frac{\text{drift}}{\Delta U}$



2nd consequence: Thevenin-Norton theorem



 $\overline{v^2} = 4KTR\Delta f$

 $\overline{i^2} = 4KTG\Delta f$



- Total current conservation = zero-sum rule (Kirchhoff)
- Typical of field-effect transistors
- Channel = total current branching between source-drain and channel-gate directions

Aim of the study

Discuss problems related to the intrinsic noise in FET channels induced by the continuous branching of the total current between 3 terminals







 $J_c(n) - J_c(n-1) + J_g(n) = 0$









Circuit model: impedance network



Circuit model: impedance network



Circuit model: impedance network



Source

Drain

$$J_i^{disp}(n) = -C_i(n) \frac{d}{dt} \begin{cases} \left[\varphi(n+1) - \varphi(n)\right] &, i=0\\ \left[U_G - \tilde{\varphi}(n)\right] &, i=0 \end{cases}$$

$$\left[C_c(n)\frac{d}{dt}[\varphi(n+1)-\varphi(n)]+J_c^d(k)\right]-$$

$$\left[C_c(n-1)\frac{d}{dt}[\varphi(n)-\varphi(n-1)]+J_c^d(n-1)\right]=$$

$$-\left[C_g(n)\frac{d}{dt}[U_G - \tilde{\varphi}(n)] + J_g^d(n)\right]$$

$$\left[C_c(n)\frac{d}{dt}[\varphi(n+1)-\varphi(n)]+J_c^d(k)\right]-$$

$$\left[C_c(n-1)\frac{d}{dt}[\varphi(n)-\varphi(n-1)]+J_c^d(n-1)\right] = \ln \frac{d}{dt}\left[\varphi(n)-\varphi(n-1)\right] + \frac{d}{dt}\left[\varphi(n-1)-\varphi(n-1)\right] + \frac{d}{dt}\left[\varphi(n-1)-\varphi(n-1)-\varphi(n-1)\right] + \frac{d}{dt}\left[\varphi(n-1)-\varphi(n-1)\right] + \frac{d}{dt}\left[$$

$$-\left[C_g(n)\frac{d}{dt}[U_G - \tilde{\varphi}(n)] + J_g^d(n)\right]$$

$$\left[C_c(n)\frac{d}{dt}[\varphi(n+1)-\varphi(n)]+J_c^d(k)\right] - \text{Out source} \rightarrow \text{drain}$$

$$\left[C_c(n-1)\frac{d}{dt}[\varphi(n)-\varphi(n-1)]+J_c^d(n-1)\right] = \ln \frac{d}{dt}\left[\varphi(n)-\varphi(n-1)\right] + \frac{d}{dt}\left[\varphi(n-1)-\varphi(n-1)\right] + \frac{d}{dt}\left[\varphi(n-1)-\varphi(n-1)-\varphi(n-1)\right] + \frac{d}{dt}\left[\varphi(n-1)-\varphi(n-1)\right] + \frac{d}{dt}\left[$$

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$$-\left[C_g(n)\frac{d}{dt}[U_G - \tilde{\varphi}(n)] + J_g^d(n)\right]$$

Out channel
$$\rightarrow$$
 gate

$$\left[C_c(n)\frac{d}{dt}[\varphi(n+1)-\varphi(n)]+J_c^d(k)\right] - \text{Out source} \rightarrow \text{drain}$$

$$\left[C_c(n-1)\frac{d}{dt}[\varphi(n)-\varphi(n-1)]+J_c^d(n-1)\right] = \Box$$

$$-\left[C_g(n)\frac{d}{dt}[U_G - \tilde{\varphi}(n)] + J_g^d(n)\right]$$

Out channel \rightarrow gate

by taking the limit $\Delta x \to 0$ and normalizing to the cross-section $S = W\delta$...

Conservation of total current in differential form

Total

 $\frac{d}{dx}[j_c(x)] + \frac{1}{\delta}j_g(x) = 0$

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Channel

$$j_{c}(x) = -\epsilon_{c}\epsilon_{0}\frac{d}{dt}\frac{\partial}{\partial x}\varphi(x) + j_{c}^{d}(x)$$

Conservation of total current in differential form

Total

$$\frac{d}{dx}[j_c(x)] + \frac{1}{\delta}j_g(x) = 0$$

Channel
$$j_c(x) = -\epsilon_c \epsilon_0 \frac{d}{dt} \frac{\partial}{\partial x} \varphi(x) + j_c^d(x)$$

Gate

$$j_g(x) = -\frac{\epsilon_d \epsilon_0}{d(x)} \frac{d}{dt} [U_G - \varphi(x)] + j_g^d(x)$$

Conservation of total current in integral form By integrating between source (x=0) and drain (x=L)



Quasi-2D Poisson equation

By using the charge conservation law

 $\frac{\partial}{\partial t}\rho^{3D}(x) + \frac{\partial}{\partial x}j_c^d(x) + \frac{j_g^a(x)}{\delta} = 0$



 $\epsilon_c \frac{\partial^2}{\partial x^2} \varphi(x) + \frac{\epsilon_d}{d(x)\delta} [U_g - \varphi(x)] = -\frac{1}{\epsilon_0} \rho^{3D}(x)$

Quasi-2D Poisson equation

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Longitudinal field

$$\frac{\partial^2}{\partial x^2}\varphi(x) + \frac{\epsilon_d}{d(x)\delta}[U_g - \varphi(x)] = -\frac{1}{\epsilon_0}\rho^{3D}(x)$$

Quasi-2D Poisson equation

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Longitudinal field Gate field

$$\epsilon_c \frac{\partial^2}{\partial x^2} \varphi(x) + \frac{\epsilon_d}{d(x)\delta} [U_g - \varphi(x)] = -\frac{1}{\epsilon_0} \rho^{3D}(x)$$

Ist limit of quasi-2D Poisson equation

Narrow channel $\delta \rightarrow 0$



$\delta \epsilon_0 \epsilon_c \frac{\partial^2}{\partial x^2} [\varphi(x)] + \frac{\epsilon_0 \epsilon_d}{d(x)} [U_g - \varphi(x)] = -\rho^{3D}(x) \delta$

$\delta \epsilon_0 \epsilon_c \frac{\partial^2}{\partial x^2} [\varphi(x)] + \frac{\epsilon_0 \epsilon_d}{d(x)} [U_g - \varphi(x)] = -\rho^{3D}(x) \delta$
Ist limit of quasi-2D Poisson equation *Gate* Narrow channel $\delta \rightarrow 0$ *Source*

$$\delta \epsilon_0 \epsilon_c \frac{\partial^2}{\partial x^2} [\varphi(x)] + \frac{\epsilon_0 \epsilon_d}{d(x)} [U_g - \varphi(x)] = -\rho^{3D}(x)\delta$$

$$C_g V_0 = -eN^{2D}(x)$$

Gradual channel approximation



2nd limit of quasi-2D Poisson equation $\int_{d} \int_{d} \int_{d$

$$\frac{\partial^2}{\partial x^2}\varphi(x) + \frac{\epsilon_d}{\epsilon_c d(x)\delta} [U_g - \varphi(x)] = -\frac{1}{\epsilon_0\epsilon_c} \rho^{3D}(x)$$

2nd limit of quasi-2D Poisson equation

$$\int_{d} \int_{d} \int_{d}$$



ID Poisson equation

- No transport to gate $\rightarrow j_g^d(x) = 0$
- Drift current in the channel $\rightarrow j_c^d(x) = en^{3D}(x)v(x)$

Velocity from hydrodynamic approach

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- Drift current in the channel $\rightarrow j_c^d(x) = en^{3D}(x)v(x)$

Velocity from hydrodynamic approach

$$\frac{\partial}{\partial t}v + \frac{\partial}{\partial x}\left[\frac{v^2}{2} + \frac{e}{m}\varphi(x)\right] + e\nu D\frac{\partial}{\partial x}n^{3D}(x) = -\nu v + \tilde{f}$$

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Velocity from hydrodynamic approach

$$\begin{split} \frac{\partial}{\partial t}v + \frac{\partial}{\partial x}\left[\frac{v^2}{2} + \frac{e}{m}\varphi(x)\right] + e\nu D\frac{\partial}{\partial x}n^{3D}(x) = -\nu v + \tilde{f} \\ & \text{Velocity} \\ & \text{relaxation rate} \end{split}$$

- No transport to gate $\rightarrow j_g^d(x) = 0$
- Drift current in the channel $\rightarrow j_c^d(x) = en^{3D}(x)v(x)$

• Velocity from hydrodynamic approach Diffusion coefficient

$$\begin{split} \frac{\partial}{\partial t}v + \frac{\partial}{\partial x} \left[\frac{v^2}{2} + \frac{e}{m}\varphi(x) \right] + e\nu D \frac{\partial}{\partial x} n^{3D}(x) = -\nu v + \tilde{f} \\ & \text{Velocity} \\ & \text{relaxation rate} \end{split}$$

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• Velocity from hydrodynamic approach Diffusion coefficient

$$\frac{\partial}{\partial t}v + \frac{\partial}{\partial x} \left[\frac{v^2}{2} + \frac{e}{m}\varphi(x) \right] + e \frac{\partial}{\partial x} \frac{\partial}{\partial x} n^{3D}(x) = -\frac{\partial}{\partial x}v + \frac{f}{f}$$
Velocity
Langevin
relaxation rate
force

Analytical Model

- Carrier concentration in the channel n_0
- No drift velocity $v_0 = 0$
- Linearization of equations
- Neglecting diffusion current

Linearized equations in frequency domain

• Potential
$$\frac{d^2}{dx^2}\Delta\varphi(x) + \lambda^2[\Delta U_g - \Delta\varphi] = -\frac{e}{\epsilon\epsilon_0}\Delta n$$

• Concentration
$$e\Delta n = -\frac{1}{i\omega}\frac{d}{dx}\Delta j_d$$

• Drift current
$$\Delta j_d(x) = en_0 \Delta v = \epsilon \epsilon_0 \frac{\omega_p^2}{i\omega + \nu} \left[\tilde{f} - \frac{\partial}{\partial x} \Delta \varphi \right]$$

Self-consistent fluctuating potential

$$\frac{d^2}{dx^2}\varphi - \beta^2\varphi = -\beta^2\Delta U_g + \frac{d}{dx}\tilde{f}$$

where
$$\beta^2 = \lambda^2 [i\omega(i\omega + \nu)/(\omega_p^2 + i\omega(i\omega + \nu))]$$

Solved using Green functions

$$G(x, x_0) = \frac{1}{\beta} \left[-\frac{sh\beta(L - x_0)}{sh\beta L} sh\beta x_0 + Z(x - x_0)sh\beta(x - x_0) \right]$$

Solution in common source configuration

$$\Delta \mathbf{J} = \begin{bmatrix} \Delta J_d \\ \Delta J_g \end{bmatrix}, \quad \Delta \mathbf{U} = \begin{bmatrix} \Delta U_d \\ \Delta U_g \end{bmatrix} \qquad \Delta \mathbf{J} = \hat{Y} \Delta \mathbf{U} + \xi_J$$

Admittance

$$\hat{Y} = \epsilon \epsilon_0 \frac{\omega_p^2 + i\omega(i\omega + \nu)}{i\omega + \nu} \frac{\beta sh\beta \frac{L}{2}}{ch\beta \frac{L}{2}} \begin{pmatrix} -\frac{ch\beta L}{ch\beta L - 1} & 1\\ 1 & -2 \end{pmatrix}$$

Norton generator of current noise

 $\xi_J = \epsilon \epsilon_0 \frac{\omega_p^2 \beta}{i\omega + \nu} \int_0^L \left[\frac{ch\beta x_0/sh\beta L}{sh\beta(\frac{L}{2} - x_0)/ch\beta\frac{L}{2}} \right] \tilde{f}(x_0) dx_0$

 $\begin{cases} L = 1000 \text{ nm} \\ \delta = 15 \text{ nm} \\ d = 15 \text{ nm} \\ N_D^{3D} = 8 \times 10^{17} \text{ cm}^{-3} \\ 30 + 30 \text{ nm ungated} \\ \nu = 3 \times 10^{12} \text{ s}^{-1} \\ m^* = 0.048m_0 \end{cases}$

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$$S_{\xi\xi}(\omega) = \int_0^L n^{3D} |G_{\xi}(\omega, x_0)|^2 S_{ff} dx_0$$

 $\left\{ egin{array}{ll} L = 1000 \ {
m nm} \ \delta = 15 \ {
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ight.$

$$S_{\xi\xi}(\omega) = \int_0^L n^{3D} \frac{|G_{\xi}(\omega, x_0)|^2}{|G_{\xi}(\omega, x_0)|^2} S_{ff} dx_0$$

Transfer
field

 $\begin{cases} L = 1000 \text{ nm} \\ \delta = 15 \text{ nm} \\ d = 15 \text{ nm} \\ N_D^{3D} = 8 \times 10^{17} \text{ cm}^{-3} \\ 30 + 30 \text{ nm ungated} \\ \nu = 3 \times 10^{12} \text{ s}^{-1} \\ m^* = 0.048m_0 \end{cases}$

$$S_{\xi\xi}(\omega) = \int_0^L n^{3D} |G_{\xi}(\omega, x_0)|^2 S_{ff} dx_0$$

TransferSpectral density offieldLangevin force $= 4k_B T \nu / m^*$

Effect of time delay

Spectra of current fluctuations

- Resonances in the THz domain
- Ungated regions suppresses HF peaks
- Different resonances at source and gate

Unsolved problem #1

Is it possible to measure electronic noise at TeraHertz frequencies?

Challenge for experiments

Plasma waves in semiconductors

Travelling plasma waves

Travelling plasma waves Gate

Plasma modes in field-effect transistors

$$\omega_{res}^{i}(n) = \omega_{p}^{3D} \frac{n}{\sqrt{(\lambda L/\pi)^{2} + n^{2}}} \begin{cases} n = 0, 1, 2, \dots, i = d \\ n = 1, 3, 5, \dots, i = g \end{cases}$$

3D plasma frequency geometry factor $\lambda = \sqrt{\epsilon_d/\epsilon_c d\delta}$

Unsolved problem #2

Is it possible to exploit plasma waves to obtain a detector or emitter of TeraHertz radiation?

Huge number of potential applications

From ungated to gated transistor

From ungated to gated transistor

Unsolved problem #3

Which is the physical origin of the excess noise?

The system is at equilibrium and total noise power increases (not simple noise redistribution)

Noise vs operation mode





closed









Unsolved problem #4

Which is the intrinsic noise of the transistor?

Noise spectra depend on operating conditions Failure of Thevenin/Norton equivalence?

Conclusions

- Novel circuit + analytical model
- Thermal fluctuations excite standing plasma waves at THz frequencies
- Current branching strongly influences intrinsic noise spectra

unsolved problem on branching

